TOSHIBA Photocoupler GaAlAs Ired & Photo IC

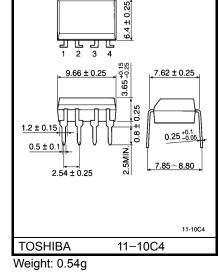
TLP559

Digital Logic Ground Isolation Line Receiver Microprocessor System Interfaces Switching Power Supply Feedback Control Transistor Invertor

The TOSHIBA TLP559 consists of a GaAlAs high–output light emitting diode and a high speed detector of one chip photo diode–transistor. This unit is 8–lead DIP package.

TLP559 has no internal base connection, and a faraday shield integrated on the photodetector chip provides an effective common mode noise transient immunity.

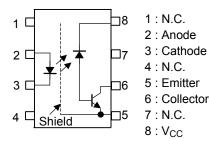
So this is suitable for application in noisy environmental condition.



876 5175

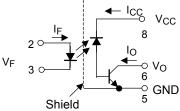
- Isolation voltage: 2500Vrms (min.)
- Switching speed: t_{pHL} = 0.3µs (typ.)
 - $t_{pLH} = 0.5 \mu s (typ.) (R_L = 1.9 k\Omega)$
- TTL compatible
- UL recognized: UL1577, file No.E67349

Pin Configuration (top view)





Schematic



Unit in mm

Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
LED	Forward current	(Note 1)	١ _F	25	mA
	Pulse forward current	(Note 2)	I _{FP}	50	mA
	Peak transient forward current	(Note 3)	I _{FPT}	1	А
	Reverse voltage		VR	5	V
	Diode power dissipation	(Note 4)	PD	45	mW
Detector	Output current		Ι _Ο	8	mA
	Peak output current		I _{OP}	16	mA
	Output voltage		VO	-0.5~15	V
	Supply voltage		V _{CC}	-0.5~15	V
	Output power dissipation	(Note 5)	PO	100	mW
Ope	erating temperature range		T _{opr}	-55~100	°C
Stor	Storage temperature range			-55~125	°C
Lea	Lead solder temperature (10s) (Note 6			260	°C
Isol	Isolation voltage (AC, 1 min., R.H. ≤ 60%) (Note 7		BVS	2500	Vrms

(Note 1) Derate 0.8mA above 70°C.

- (Note 2) 50% duty cycle,1ms pulse width. Derate 1.6mA / °C above 70°C.
- (Note 3) Pulse width $\leq 1\mu$ s, 300pps.
- (Note 4) Derate 0.9mW / °C above 70°C.
- (Note 5) Derate 2mW / °C above 70°C.
- (Note 6) Soldering portion of lead: up to 2mm from body of the devise.
- (Note 7) Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.

Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit	
LED	Forward voltage	VF	I _F = 16mA	_	1.65	1.85	V	
	Forward voltage temperature coefficient	ΔV _F / ΔTa	I _F = 16mA	_	-2		mV / °C	
	Reverse current	I _R	V _R = 5V	—	—	10	μΑ	
	Capacitance between terminal	CT	V _F = 0, f = 1MHz	-	45		pF	
Detector	High level output current	I _{OH (1)}	I _F = 0mA, V _{CC} = V _O = 5.5V	_	3	500	nA	
		I _{OH (2)}	I _F = 0mA, V _{CC} = V _O = 15V	_		5		
		ЮН	I _F = 0mA, V _{CC} = 15V V _O = 15V, Ta = 70°C	_	_	50	μA	
	High level supply voltage	ICCH	I _F = 0mA, V _{CC} = 15V	_	0.01	1	μA	
Coupled	Current transfer ratio	I _O / I _F	I_F = 16mA, V_{CC} = 4.5V V_O = 0.4V	20	40	_	%	
	Low level output voltage	V _{OL}	I _F = 16mA, V _{CC} = 4.5V I _O = 2.4mA	_	_	0.4	V	
	Resistance (input-output)	R _S	R.H. ≤ 60%, V _S = 500V _{DC} (Note 7)	5×10 ¹⁰	10 ¹⁴	_	Ω	
	Capacotance (input-output)	CS	$V_{S} = 0, f = 1MHz$ (Note 7)	—	0.8	_	pF	

Switching Characteristics (Ta = $25^{\circ}C$, V_{CC} = 5V)

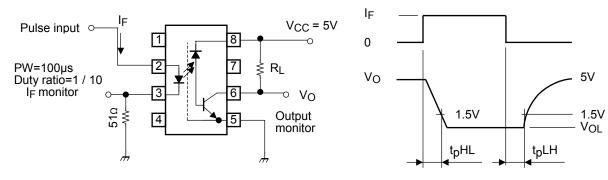
Characteristic		Symbol	Test Cir– cuit	Test Condition	Min.	Тур.	Max.	Unit
Propagation delay time	$(H{\rightarrow}L)$	^t pHL	1	I _F = 16mA, R _L = 1.9kΩ	_	0.2	0.8	μs
Propagation delay time	$(L{\rightarrow}H)$	t _{pLH}			_	0.3	0.8	μs
Common mode transient immunity at logic high output	(Note 8)	CM _H	- 2	I _F = 0mA, V _{CM} = 400V _{p-p} R _L = 4.1kΩ	2000	10000	_	V / µs
Common mode transient immunity at logic high output	(Note 8)	CML		I _F =16mA, V _{CM} = 400V _{p-p} R _L = 4.1kΩ	-2000	-10000	_	V / µs

(Note 8) CM_L is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state ($V_O < 0.8V$).

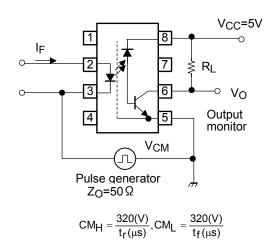
 CM_H is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state (V_O < 2.0V).

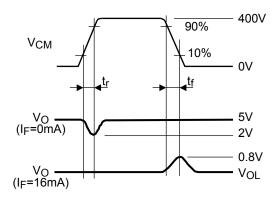
(Note 9) Maximum electrostatic discharge voltage for any pins: 100V (C = 200pF, R = 0)

Test Circuit 1: Switching Time Test Circuit

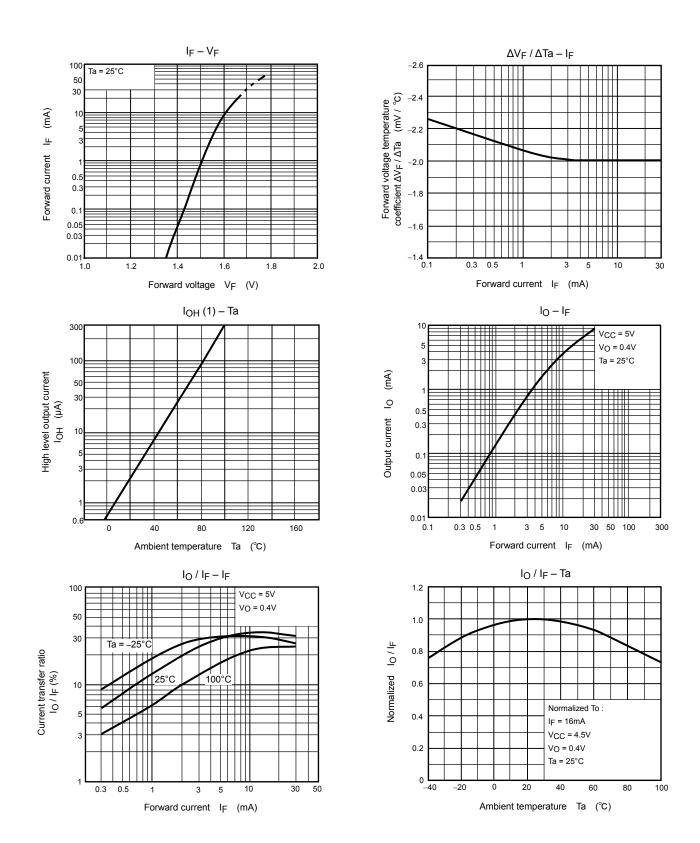


Test Circuit 2: Common Mode Noise Immunity Test Circuit

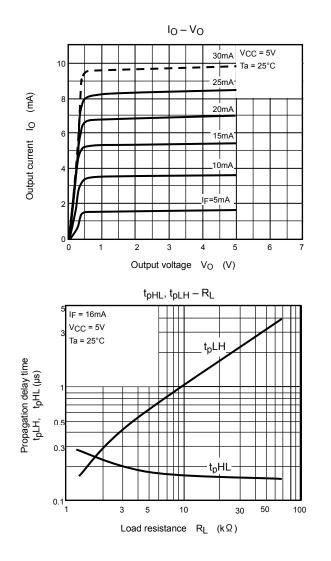


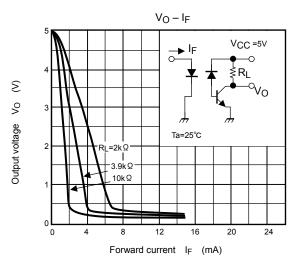


TOSHIBA



TOSHIBA





RESTRICTIONS ON PRODUCT USE

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
 In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as act facth in the most responsibility and reliability of the products and the products and the product of the produ

set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.

- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.).These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- GaAs(Gallium Arsenide) is used in this product. The dust or vapor is harmful to the human body. Do not break, cut, crush or dissolve chemically.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.